



The  
University  
Of  
Sheffield.

## DEPARTMENT OF ELECTRONIC AND ELECTRICAL ENGINEERING

### EEE118 Electronic Devices and Circuits

Mid-year test Jan 2014

#### Student Registration Number:

*as shown on U.Card, but not U.Card number*

Mass of free electron,  $m_e = 9.11 \times 10^{-31}$  kg

Charge on electron,  $q = 1.60 \times 10^{-19}$  C

Boltzmann constant,  $k_B = 1.38 \times 10^{-23}$  J/K

$$C = \frac{\epsilon_0 \epsilon_r A}{d}$$

$$\mu = \frac{q\tau}{m^*}$$

$$E = -\frac{dV}{dx}$$

$$J = qD \frac{dn}{dx}$$

$$R = \rho L/A \quad \rho = 1/\sigma \quad D = \frac{kT}{q} \mu$$

$$L = \sqrt{D\tau}$$

$$\partial p = \partial p_0 \exp\left(\frac{-x}{L_h}\right)$$

$$\langle v_d \rangle = -\mu E$$

Permittivity of free space,  $\epsilon_0 = 8.85 \times 10^{-12}$  F/m

Planck's constant,  $h = 6.63 \times 10^{-34}$  Js

$$\text{Poisson's Equation} \quad \frac{d^2V}{dx^2} = -\frac{\rho}{\epsilon}$$

Energy of a photon  $= hc/\lambda$

$$\sigma = \frac{1}{\rho} = ne\mu_e + pe\mu_h$$

$$n_i = C T^{3/2} \exp\left(-\frac{E_g}{2k_B T}\right)$$

$$n_i^2 = n_n p_n = n_p p_p$$

$$\langle v_d \rangle = -\frac{qE\tau}{m^*}$$

**Answer all questions by writing the answer in the box provided** (there is no requirement to show workings on this sheet)

**One mark per question, unless indicated**

1	<p>Which <b>one</b> of the following statements is correct?</p> <p>The mobility of an electron in a semiconductor is a measure of:</p> <ul style="list-style-type: none"> <li>A. how quickly it will recombine with a hole.</li> <li>B. how fast it will drift through a device per unit applied electric field.</li> <li>C. the energy it emits when it recombines with a hole.</li> <li>D. the time between collisions with crystal defects.</li> </ul>	B
2	<p>Which <b>one</b> of the following statements about the magnitude of the built-in voltage of a diode is true?</p> <ul style="list-style-type: none"> <li>A. It is a measure of the voltage to be overcome by an applied external forward bias to achieve conduction.</li> <li>B. This is the voltage that would be measured at the diode terminals with zero external voltage applied.</li> <li>C. It is the external voltage to be applied to stop any current flow in the diode.</li> <li>D. It is the voltage where the diode will suffer breakdown failure.</li> </ul>	A
3	<p>Which <b>one</b> of the following statements is true?</p> <p>The capacitance of a zero biased p-n junction diode will:</p> <ul style="list-style-type: none"> <li>A. decrease as the p and n doping is increased.</li> <li>B. increase when the diode area decreases.</li> <li>C. decrease as the p and n doping is decreased.</li> <li>D. decrease when either the p or the n region doping is increased.</li> </ul>	C
4	<p>In an n-type semiconductor, the electron concentration is decreasing from left to right.</p> <p>Which <b>two</b> of the following statements are true?</p> <ul style="list-style-type: none"> <li>A. Diffusion causes the electrons to move from right to left.</li> <li>B. Diffusion causes the electrons to move from left to right.</li> <li>C. An electric field from right to left is required to balance this diffusion movement.</li> <li>D. An electric field from left to right is required to balance this diffusion movement.</li> </ul>	B, D (1/2 mark each)
5	<p>What is the resistance of a rod that is 0.1 m long, <math>5 \times 10^{-6} \text{ m}^2</math> in cross-sectional area, and which has a conductivity of <math>500 \Omega^{-1} \text{ m}^{-1}</math> (<i>use the appropriate equations on the first page</i>).</p>	40Ω
6	<p>Which <b>one</b> of the following statements correctly describes the charge carrier known as a “hole” is in a semiconductor:</p> <ul style="list-style-type: none"> <li>A. The gap left in a semiconductor crystal when an atom is removed is called a hole.</li> <li>B. When an electron is given sufficient energy to leave its crystal bond a hole is formed in the bond.</li> <li>C. When an electron moves across a p-n junction due to forward bias a hole is formed where it used to be.</li> <li>D. A donor atom ‘donates’ a free electron to the semiconductor leaving behind a positive charge known as a hole.</li> </ul>	B
7	<p>For a certain concentration of minority holes injected into one side of a semiconductor, calculate the fraction that remain 1 μm away from that side if the minority carrier diffusion length for holes is 2 μm. (<i>a suitable equation from the first page can be used for the calculation</i>)</p>	0.61

<p>8 The relative dielectric constant (<math>\epsilon_r</math>) for a certain ceramic insulator is 50. This insulator is used to fill the gap between the parallel plates of a capacitor which previously had air between the plates. How will this affect the capacitance value relative to the air-filled capacitor and by how much?</p>	<p><b>Increase by 50 times</b> (1/2 mark for each point)</p>
<p>9 Which <b>one</b> of the following statements is true.</p> <p>An LED emitting blue light</p> <p><b>A.</b> is made from a crystal which has a weaker crystal bond compared to that used for a red LED.</p> <p><b>B.</b> has a much higher doping concentration compared to a red LED.</p> <p><b>C.</b> can be made from silicon crystal.</p> <p><b>D.</b> is made from a crystal which is harder compared to that used for a green LED.</p>	<p><b>D</b></p>
<p>10 Complete the following statement using <b>one</b> of the alternatives:</p> <p>The process of diffusion of electrons in a semiconductor</p> <p><b>A.</b> results from the movement of electrons from low concentrations to high concentrations.</p> <p><b>B.</b> will increase as the temperature decreases.</p> <p><b>C.</b> will increase as both the concentration gradient and the temperature increases</p> <p><b>D:</b> needs the presence of an electric field.</p>	<p><b>C</b></p>
<p>11 A piece of silicon is doped n-type to a value <math>1 \times 10^{23} \text{ m}^{-3}</math>. What is the minority carrier concentration if the intrinsic value is <math>1.45 \times 10^{10} \text{ m}^{-3}</math>?</p>	<p><b><math>2.1 \times 10^{-3} \text{ m}^{-3}</math></b></p>
<p>12 Which <b>one</b> of the following statements is closest to the truth:</p> <p>The small reverse biased leakage or saturation current in a p-n junction diode is mainly due to:</p> <p><b>A.</b> the diffusion of majority carriers from their respective sides over the built-in barrier.</p> <p><b>B.</b> current leakage around the edge of the diode.</p> <p><b>C.</b> crystal defects.</p> <p><b>D.</b> thermally generated electron-hole pairs within the depletion region.</p>	<p><b>D</b></p>
<p>13 Draw the circuit symbol for a diode <b>and</b> label the anode and cathode <b>(1 mark)</b>.</p>	
<p>14 Add two arrows on your diagram in Q13 which show,</p> <ul style="list-style-type: none"> <li>the direction of current flow when the diode is <i>forward biased</i> above the turn on voltage. Label this arrow <i>I</i>.</li> <li>the direction of the voltage which forward biases the diode. Label this arrow <i>V</i>. <b>(1 mark)</b></li> </ul>	

15

What does “on the edge of conduction” mean when considering a diode? (1 mark)

- 16 For the circuit in Fig. 1, find the value of  $V_i$  that puts the diode on the edge of conduction (3 marks)

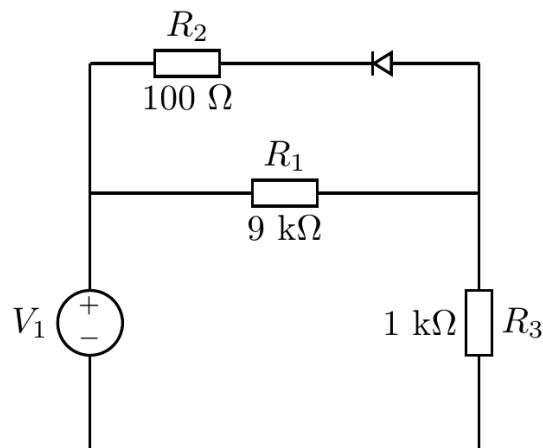


Fig. 1

- 17 A diode, resistor, capacitor circuit is shown in Fig. 2. The input pulse,  $V_i$  is shown in Fig 3.

Draw, on Fig. 3, the shape of the capacitor voltage,  $V_o$  waveform due to the input (1 mark)

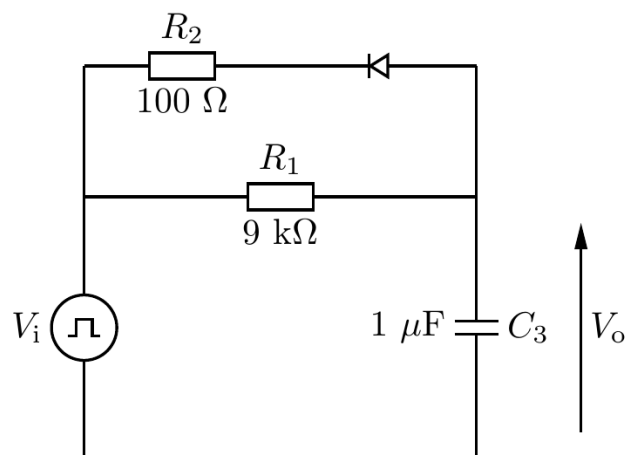


Fig. 2

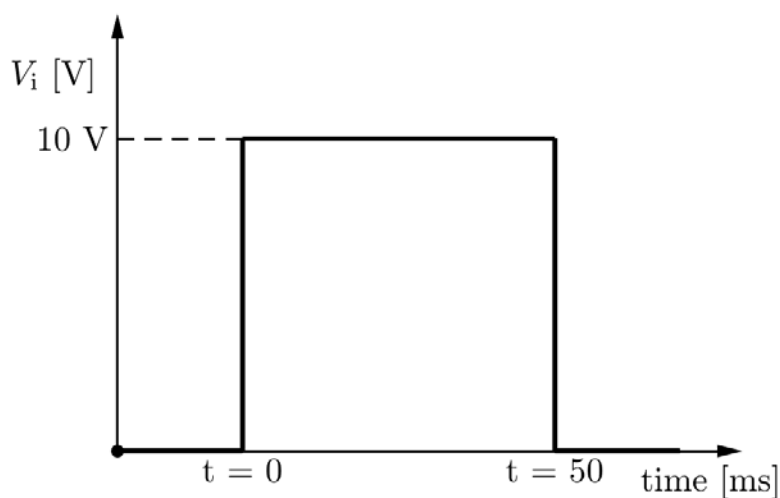
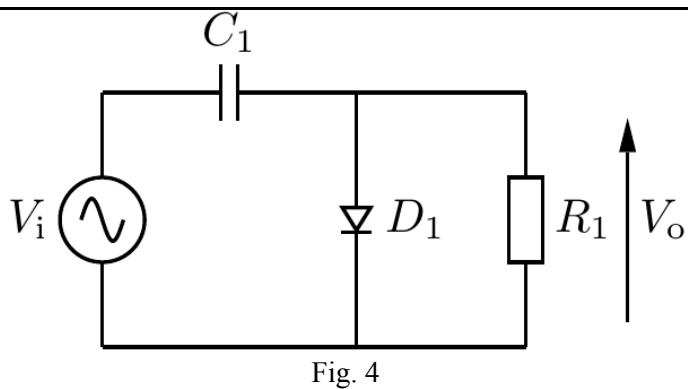


Fig. 3

18 State algebraically (i.e. in terms of  $R_1$ ,  $R_2$  &  $C_3$ ) **both** time constants associated with the circuit in Fig. 2. (1 mark)

19 Calculate the voltage across the capacitor for  $t = 9$  ms (1 mark)

20 Name the circuit in Fig. 4. (1 mark)

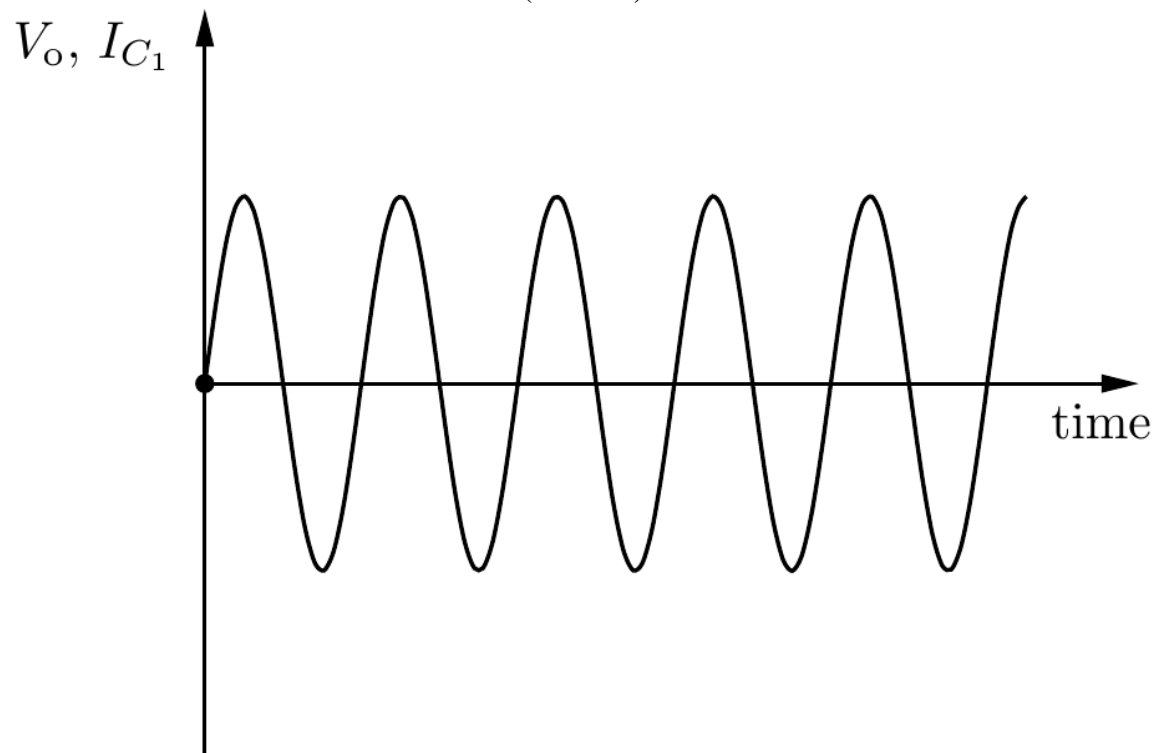


21

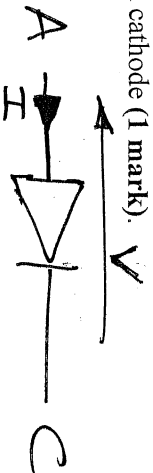
Consider the circuit in Fig. 4 driven by the sine wave input below. Sketch on the axes below

- The output voltage,  $V_o$
- The capacitor current,  $I_{C1}$ .

(2 marks)



**END OF PAPER**

<p>10 <i>Complete the following statement correctly:</i> As the temperature is increased from room temperature the resistivity of an intrinsic semiconductor</p> <p><b>A:</b> will decrease as extra electrons and holes are created to become free to move in the material.  <b>B:</b> will decrease as the effective masses of the electrons and holes become less and so they become easier to move  <b>C:</b> will increase as the effective masses of the electrons and holes become more and so become harder to move  <b>D:</b> will stay the same as the resistivity depends on the materials properties, such as the defect density in the material and these do not change with temperature.</p>	
<p>11 A very short pulse of light is shone uniformly onto an n-type semiconductor sample, creating <math>10^{20} \text{ m}^{-3}</math> electron-hole pairs. The minority carrier lifetime is 100 ns. How many holes are left after 0.5 <math>\mu\text{s}</math>? [Hint: the equation you need to use is in the form of an exponential decay with time]</p> <p>12 Which <i>two</i> of the following statements are true:  For an LED to emit light:  <b>A.</b> A pn junction is required  <b>B.</b> It needs to be forward biased  <b>C.</b> It needs to be reverse biased  <b>D.</b> It can be made from silicon</p>	
<p>13 Draw the circuit symbol for a diode <i>and</i> label the anode and cathode (1 mark).</p> 	
<p>14 Add two arrows on your diagram in Q13 which show,  <ul style="list-style-type: none"> <li>the direction of current flow when the diode is <i>forward biased</i> above the turn on voltage. Label this arrow <i>I</i>.</li> <li>the direction of the voltage which forward biases the diode. Label this arrow <i>V</i>.</li> </ul> (1 mark)</p>	
<p>15 What does "on the edge of conduction" mean when considering a diode? (1 mark)</p> <p>O.7 V ACROSS THE DIODE WHEN THE ANODE IS MORE POSITIVE THAN THE CATHODE <u>AND</u> NO CURRENT FLOWS IN THE DIODE</p>	

- 16 For the circuit in Fig. 1, find the value of  $V_1$  that puts the diode on the edge of conduction (3 marks)

IF Diode NOT conducting,

$$I R_2 = 0 \quad A_{D0} \quad V_D = 0.7 \text{ V}$$

$$\therefore V_{R_1} = 0.7 \text{ V}$$

$$I = V_{R_1} / R_1 = \frac{0.7}{9 \text{ k}\Omega}$$

$$V_1 = -0.7 - \left( \frac{0.7}{9 \text{ k}\Omega} \cdot 1 \text{ k}\Omega \right) = -0.7777 \text{ V}$$

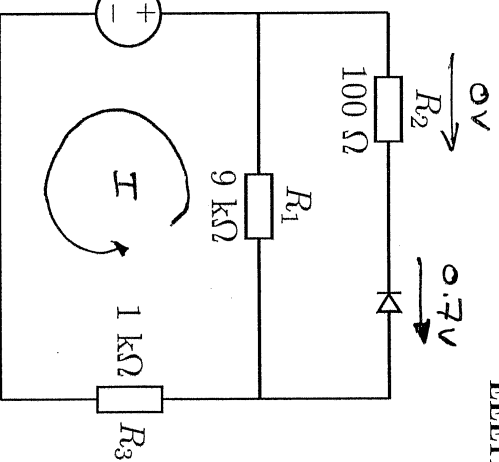


Fig. 1

- 17 A diode, resistor, capacitor circuit is shown in Fig. 2. The input pulse,  $V_1$  is shown in Fig. 3. (1 marks)

Draw, on Fig. 3, the shape of the capacitor voltage,  $V_o$  waveform due to the input

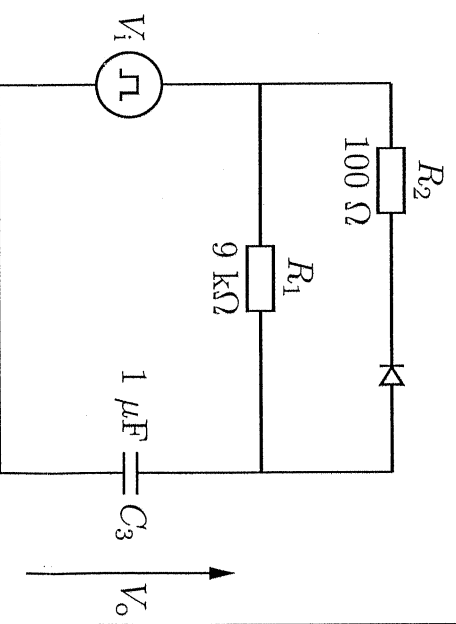


Fig. 2

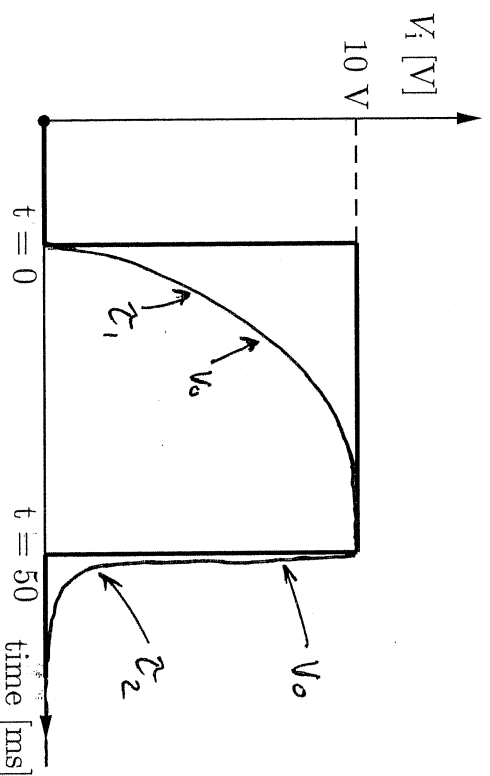


Fig. 3

- 18 State algebraically (i.e. in terms of  $R_1$ ,  $R_2$  &  $C_3$ ) both time constants associated with the circuit in Fig. 2. (1 mark)

$$\tau_1 = R_1 C_3, \quad \tau_2 = (R_2 \parallel R_1) \cdot C_3$$



19 Calculate the voltage across the capacitor for  $t = 9 \text{ ms}$  (1 mark)

6.3212 V

NOTE IT IS NOT 14.5 V  
TO SHOW WORKING !!

20 Name the circuit in Fig. 4. (1 mark)

ACCEPT

"CLAMP"

OR

NEGATIVE CLAMP

NOT  
POSITIVE CLAMP !!

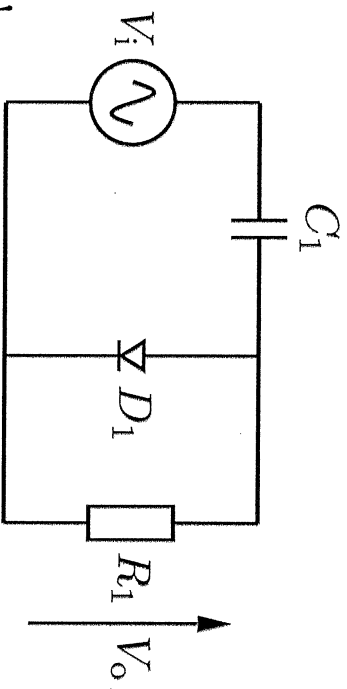
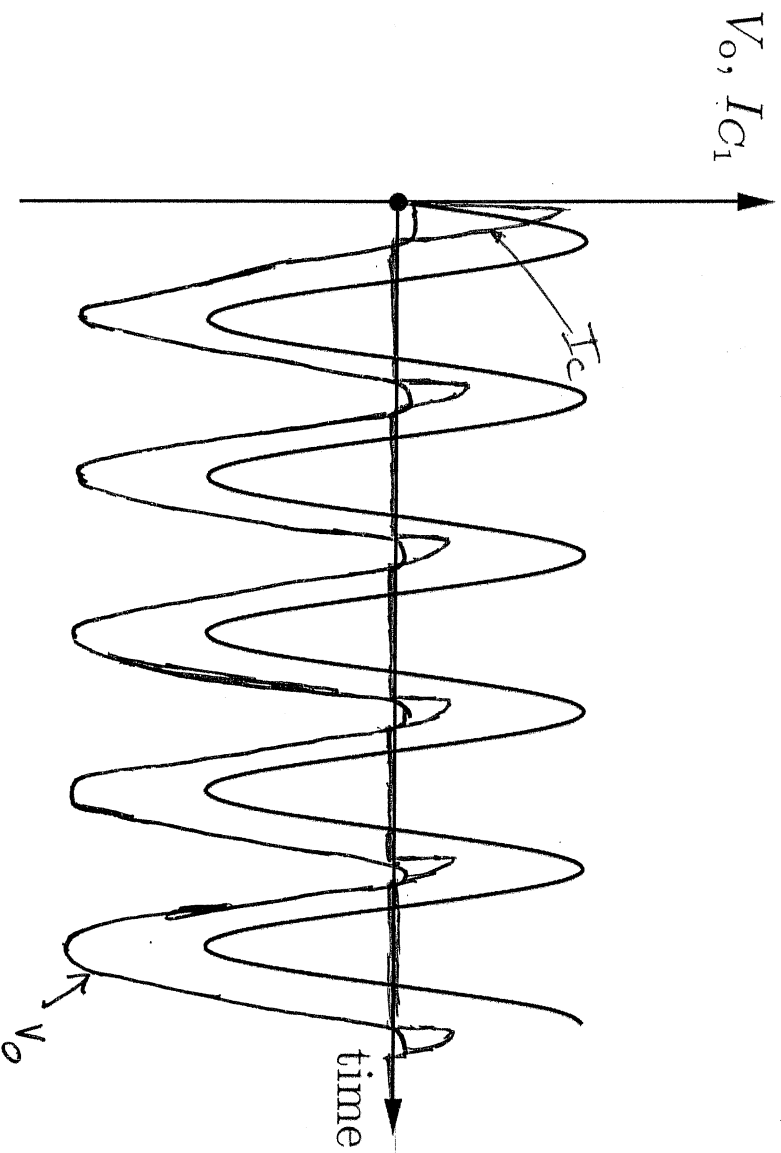


Fig. 4

21 Consider the circuit in Fig. 4 driven by the sine wave input below. Sketch on the axes below

- The output voltage,  $V_o$
- The capacitor current,  $I_{C_1}$ .

(2 marks)



END OF PAPER